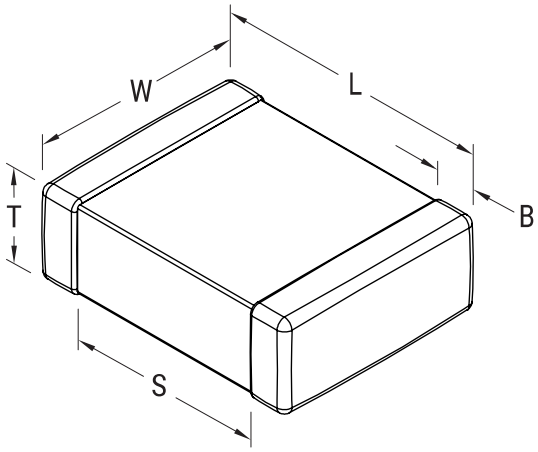
# C1206C752GBTACAUTO7210

SMD Auto X8G HVHT150C, Ceramic, 7,500 pF, 2%, 630 VDC, X8G, SMD, MLCC, High Voltage, High Temperature, Ultra-Stable, Automotive Grade, 1206 / 3216




Click here for the 3D model.

| General Information | |
|---|---|
| Series | SMD Auto X8G HVHT150C |
| Style | SMD Chip |
| Description | SMD, MLCC, High Voltage, High Temperature, Ultra-Stable, Automotive Grade |
| Features | High Temperature, Ultra-Stable, Automotive Grade |
| RoHS | Yes |
| Termination | Tin |
| Marking | No |
| Qualifications | AEC-Q200 |
| Typical Component Weight | 36 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Dimensions | |
|---|---|
| L | 3.2mm +/-0.2mm |
| W | 1.6mm +/-0.2mm |
| T | 1.6mm +/-0.15mm |
| S | 1.5mm MIN |
| B | 0.5mm +/-0.25mm |
| Case Code (EIA / mm) | 1206 / 3216 |

| Packaging Specifications | |
|---|---|
| Packaging | T&R, 330mm, Plastic Tape |
| Packaging Quantity | 8000 |

| Specifications | |
|---|---|
| Capacitance | 7,500 pF |
| Measurement Condition | 1 kHz 1.0Vrms |
| Tolerance | 2% |
| Voltage DC | 630 VDC |
| Dielectric Withstanding Voltage | 819 VDC |
| Temperature Range | -55/+150°C |
| Temp. Coefficient | X8G |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 30 ppm/C, 1kHz 1.0Vrms |
| Dissipation Factor | 0.1% 1 kHz 1.0Vrms |
| Aging Rate | 0% Loss/Decade Hour: Referee Time is 1000 Hours |
| Insulation Resistance | 100 GOhms |

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